

**Mission profile resolution impacts on the thermal stress and reliability of power devices in PV inverters**  
Sangwongwanich, Ariya; Zhou, D.; **Liivik, Elizaveta**; Blaabjerg, Frede Microelectronics reliability 2018 / p. 1003-1007  
<https://doi.org/10.1016/j.microrel.2018.06.094>